Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/716,949	GRUNDSTROM ET AL.	
Examiner	Art Unit	
Y. Lee	2621	

SEARCHED			
Class	Subclass	Date	Examiner
375	240.01 240.12 240.24 240.26	7/25/2007	YL
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